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PATENT

#5/02
J. J. J. J.
4-14-94

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Vincent J. Coates ✓

Assignee: Nanometrics Incorporated

Title: METHOD FOR DETERMINING ABSOLUTE REFLECTANCE OF A MATERIAL IN THE ULTRAVIOLET RANGE

Serial No.: 08/111,298 ✓ Filed: 08/23/93 ✓

Examiner: D. Dunn ✓ Group Art Unit: 2506

Attorney Docket No.: 8196R

Hayward, California
March 31, 1994COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, D. C. 20231REQUEST FOR RECONSIDERATION OF DECLARATION
FOR REISSUE APPLICATION AND AMENDMENT

Sir:

In response to the Office Action dated 01/03/94, please amend the above identified reissue application as follows. These changes are in addition to the proposed changes in the original Reissue Application. Also submitted concurrently herewith is a Substitute Declaration for Reissue Application, a corroboration Declaration, and a substitute cut-up duplicate of the original patent showing, column by column, the changes to be made.

IN THE SPECIFICATION

Col. 1, line 36: please amend the paragraph to show all the changes from the patent text (MPEP 1453 last paragraph) as follows:

cu
A Briefly described, the method involves the steps of measuring the reflectance of a known material, such as single crystal silicon or aluminum specimen, at the desired wavelength, computing the value of absolute reflectance from the index of refraction and absorption data available in [myriads of] handbooks, and then dividing the absolute value into [by] the measured value to derive a [product of all optical system coefficients] system efficiency coefficient. This value of the coefficient[s] is stored. An unknown material is then tested with the same unchanged optical system and at the same wavelength to obtain a measured reflectance